L Number	Hits	Search Text	DB	Time stamp
1	1	("20030073295").PN.	USPAT;	2003/11/12
2	1	("20030001242").PN.	US-PGPUB USPAT;	14:16   2003/11/12
3	13	(HSG or (hemispheric adj grain adj   polysilicon)) and (GeSbTe or chalcogenide	US-PGPUB USPAT; US-PGPUB	14:26   2003/11/12   15:17
4	0	or (phase adj change)) (HSG or (hemispheric adj grain adj	EPO; JPO;	2003/11/12
5	0	polysilicon)) and (GeSbTe or chalcogenide or (phase adj change)) (HSG or (hemispherical adj grained adj	DERWENT; IBM_TDB EPO; JPO;	15:17
	Ĭ	<pre>polysilicon)) and (GeSbTe or chalcogenide   or (phase adj change))</pre>	DERWENT; IBM TDB	15:17
6	13	(HSG or (hemispherical adj grained adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change))	USPAT; US-PGPUB	2003/11/12 15:17
7	0	((HSG or (hemispherical adj grained adj polysilicon)) and (GeSbTe or chalcogenide	USPAT; US-PGPUB	2003/11/12 15:17
		or (phase adj change))) not ((HSG or (hemispheric adj grain adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj		
8	24615	change))) (GeSbTe or chalcogenide or (phase adj change))	USPAT; US-PGPUB	2003/11/12
9	7346	((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative	USPAT; US-PGPUB	2003/11/12 15:24
10	12	or insulator or insulating) (((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative	USPAT; US-PGPUB	2003/11/12 15:24
11	0	or insulator or insulating)) and HSG ((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative	USPAT; US-PGPUB	2003/11/12 15:24
		or insulator or insulating)) and HSG) not ((HSG or (hemispherical adj grained adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change)))		
12	2161	(((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)) and (bond or	USPAT; US-PGPUB	2003/11/12
15	1802	bonding)   ((((GeSbTe or chalcogenide or (phase adj   change))) and (dielectric or insulative   or insulator or insulating)) and (bond or	USPAT; US-PGPUB	2003/11/12 15:27
16	486	bonding)) and @ad<20011231 (((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative	USPAT; US-PGPUB	2003/11/12 15:34
17	0	or insulator or insulating)) and (bond or bonding)) and @ad<20011231) and memory (((((GeSbTe or chalcogenide or (phase	USPAT;	2003/11/12
		adj change))) and (dielectric or insulative or insulator or insulating)) and (bond or bonding)) and @ad<20011231) and memory) and hsg	US-PGPUB	15:34
18	0	<pre>(((((GeSbTe or chalcogenide or (phase</pre>	USPAT; US-PGPUB	2003/11/12 15:35
19	0	grained) (TeGeSb or GeSbTe) and (hemispherical adj	USPAT;	2003/11/12
20	1	grained) (phase with change) and (hemispherical	US-PGPUB USPAT;	15:36 2003/11/12
21	0	adj grained) (phase with change) and (hemispherical adj grained)	US-PGPUB EPO; JPO; DERWENT; IBM TDB	15:37 2003/11/12 15:53
23	2	(adhesion with (hemispherical adj grained))	EPO; JPO; DERWENT; IBM TDB	2003/11/12

24	1 (adhesio	n with (hemispherical	adj	USPAT;	2003/11/12
	grained)	)	i	US-PGPUB	15:55
25	3   (adhesio	n same (hemispherical	adj	USPAT;	2003/11/12
	grained)	)		US-PGPUB	15:56

DERWENT-ACC-NO: 1999-287070

DERWENT-WEEK: 200012

COPYRIGHT 1999 DERWENT INFORMATION LTD

TITLE: Manufacture of a stacked capacitor

structure for a DRAM

cell

----- KWIC -----

Basic Abstract Text - ABTX (1):

NOVELTY - A stacked capacitor structure for a DRAM cell is manufactured

using hemispherical grained polysilicon covered by a thin heavily doped

polysilicon layer for improved <u>adhesion</u> and reduced capacitor depletion.

**◆IEEE** TEER HOME : SEARCH TEER I SHOP I WER ACCOUNT ! CONTACT (EEE Publications/Services Standards Conferences Careers/Joba Welcome United States Patent and Trademark Office Terms IEEE Quick Links Help FAQ Peer Review Your search matched 3 of 983558 documents. O-Borne Wast Can A maximum of 3 results are displayed, 25 to a page, sorted by Relevance in descending ! Access? O-log-out You may refine your search by editing the current search expression or entering a new one the text box. Then click Search Again. - Jeannais & Magazines hemispheric grain polysilicon Conference Proceedings Search Again C> Standards Search Journal or Magazine = JNL Conference = CNF Standard = STD Or By Author ()≻ Basic 1 A 0.54 μm<sup>2</sup> self-aligned, HSG floating gate cell (SAHF — Advasoced cell) for 256 Mbit flash memories Shirai, H.; Kubota, T.; Honma, I.; Watanabe, H.; Ono, H.; Okazawa, 🕽 - Join IEEE T.; Establish (EEE Electron Devices Meeting, 1995., International, 10-13 Dec. 1995 Web Account Page(s): 653 -656 Access the HEEE Messiber Digital Library E Print Format [Abstract] [PDF Full-Text (368 KB)] IEEE CNF 2 Trends in DRAM dielectrics Tang, K.S.; Lau, W.S.; Samudra, G.S.; Circuits and Devices Magazine, IEEE, Volume: 13 Issue: 3, May 1997 Page(s): 27 -34 [Abstract] [PDF Full-Text (892 KB)] IEEE JNL 3 Fabrication and performance of selective HSG storage cells for 256 Mb and 1 Gb DRAM applications Banerjee, A.; Wise, R.L.; Plumton, D.L.; Bevan, M.; Pas, M.F.; Crenshaw, D.L.; Aoyama, S.; Mansoori, M.M.; Electron Devices, IEEE Transactions on , Volume: 47 Issue: 3 , March 2000 Page(s): 584 -592 [Abstract] [PDF Full-Text (1088 KB)] IEEE JNL

**<b>♦IEEE** SEEF HOME: SEARCH SEEF I SHOP I WEB ACCOUNT I CONTACT SEE Publications/Services Standards Conferences Welcome United States Patent and Trademark Office » Search Results Help FAO Terms IEEE ₹ Quick Links Peer Review Your search matched [0] of [985444] documents. 🐎 Bonse You may refine your search by editing the current search expression or es Freday entering | Access? O-rog-om a new one the text box. Then click search Again. hsg and gesbte Search Again Journals & Magazines Conference OR Proceedings Cr Standards Use your browser's back button to return to your original search page. Search Cr By Author Results: Oisea 🥎 🕽 Advanced No documents matched your query. Action Services Or Join IEEE Establish IEEE Web Account Access the SEEE Mensiler Digital Library Remos Miss 🔛

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2003 IEEE - All rights reserved

1 of 1 11/12/03 3:05 PM

Heer Home : Search Here : Shop	· ! WEB ACCOUNT !	Contact Hees	<b>♥IEEE</b>
Membership Publications/Services	Standards Confer	rences Lareersijoba	
LEES Xeleik			Welcome
		United States Pa	stent and Trademark Office
	rick Links	F	× Search Results
Peer Review Your searce		4.5.4	
(") Hanke	th matched [0]	of <b>[983558]</b> docur	ments.
O-Wint Can You may r	efine your sear	rch by editing the cu	rrent search expression or
Access?   entering   O-log-out   a new one	the text hav	Then click search Ag	ain
	nalcogenide	men click search Ag	
nsg and ch	h Again	***************************************	
Search Search	: <b>9</b>		
Or Conference OR			
্ৰি Standards Use your b	browser's back	button to return to	your original search page.
Chity Author Results:			
O- šasic			
() Advanced No docume	ents matched y	our query.	
O- Join IEEE			
C Establish IEEE Web Account			
O- Access the			
Digital Library			
A Point Format			

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2003 IEEE - All rights reserved

1 of 1 11/12/03 3:06 PM

RESE HOME : SEAR	CHIESE I SHOP I WEB ACCOUNT I	Contact rees	<b>♦IEEE</b>
Membership Publ	Scattons/Services Standards Confere	nces Careers/Jobs	
1333	Xplore	Welcome <b>United States Patent and</b>	
Help FAQ Ter Peer Review	ms IEEE Quick Links		× Search Results
	Your search matched [0]	of <b>[983558]</b> documents.	
O- Fod-ong Process, O- Mouse O- House	You may refine your searce entering a new one the text box. T	ch by editing the current sea hen click search Again.	arch expression or
	hsg and phase change	***************************************	
elemiest	Search Again		
Or Conference Proceedings	OR		
C) Stemdards	Use your browser's back b	outton to return to your orig	ginal search page.
Search			
Or By Author Or Basic	Results:		
Or Advanced	No documents matched yo	our query.	
O- Join ISEE O- Establish IEEE Web Account			
O Access the IEEE Mainber Digital Library			
🚐 Print Formst			

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2003 IEEE — All rights reserved

1 of 1 11/12/03 3:06 PM

**♦IEEE** HEER MOME : SEARCH HEER I SHOP I WEB ACCOUNT I CONTACT HEER Publications/Services Standards Conferences Welcome United States Patent and Trademark Office » Search Results Help FAO Terms IEEE Quick Links Peer Review Your search matched [0] of [983558] documents. ( ) Home You may refine your search by editing the current search expression or C>Wint Can enterina 3 Access? a new one the text box. Then click search Again. O-Log-out hemispheric grain polysilicon and phase change Search Again Journals & Magazines Or Conference OR Proceedings 🕒 Standards Use your browser's back button to return to your original search page. Search Cr By Author Results: O- Sasio Or Advanced No documents matched your query. Annual Services O- Join 1888 Establish IEEE Web Account Access the IEEE Member Digital Library 🖴 Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2003 IEEE - All rights reserved

1 of 1 11/12/03 3:07 PM

HEER HOME : SEARC	CHIESE ( SHOP   WEE ACCOUNT	: Confact (ese	VIEEE
Kembership Publi	scations/Services Standards Confe	erences Kaseers/joba	
	Xplere		Velcome ont and Trademark Office
Peer Review	ns IEEE Quick Links	V	* Search Results
	Your search matched [0	] of [985444] docume	ents.
O floron  Virint Can  I Access?  C Log-out	You may refine your sea entering a new one the text box. hemispherical grained polys	Then click search Agai	ent search expression or n.
O Journals & Magazines	Search Again		
Conference Proceedings	OR		
C) Standards	Use your browser's back	k button to return to yo	our original search page.
Selici .			
C- By Author C- Basic	Results:		
O- Advanced	No documents matched	your query.	
O Join IEEE O Establish IEEE Web Account			
O- Accusin the IEEE Mussiber Digital Library			
A Same Samuel			

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2003 IEEE — All rights reserved

eee kome : Seak	HODOOK GEW 1 NORS 1 BEEN HO	E : CONTACT (EEE	<b>♦IEEE</b>
Membership Publ	scations/Services Standards Co	nferences Kareers/2002	
	xpore		lcome t and Trademark Office
<u>Help FAO Terr</u> Peer Review	ns IEEE Quick Links		* Search Results
	Your search matched	[ <b>0]</b> of <b>[983558]</b> documer	its.
O Horse O What Can   Access?	entering	earch by editing the curre	·
O-rod-on	The state of the s	x. Then click search Again lysilicon and chalcogenide	
O-lournais Š Magazines	Search Again		
O- Conference Proceedings	OR		
C)- Standards	Use your browser's ba	ack button to return to you	r original search page.
Search			
Or By Author Or Sasio	Results:		
C sasse	No documents matche	d your query.	
O-Join teee			
C Establish (EEE Web Account			
O Access the EEE Member Digital Library			
Print Formst			

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account | New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online Publications | Help | FAQ| Terms | Back to Top

Copyright © 2003 IEEE — All rights reserved

1 of 1 11/12/03 3:22 PM